



Contact-free S-parameter Measurements for mmW and THz Electronics



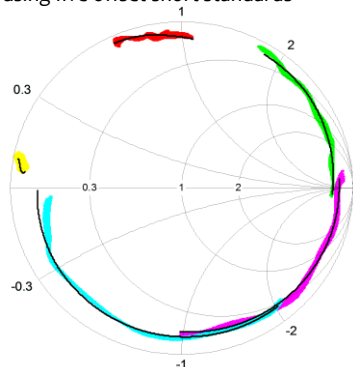
TP-100-M8025 >

Our proprietary test-bedⁱ consists of an automated probe station and virtual, contact-less probe tips, enabling, for the first time, fully-automated S-parameter characterization of electronic devices and ICs for the entire mmW and THz bands. TeraProbes test-bed enables unattended inspection of every single chip on a wafer at the fraction of the current cost.

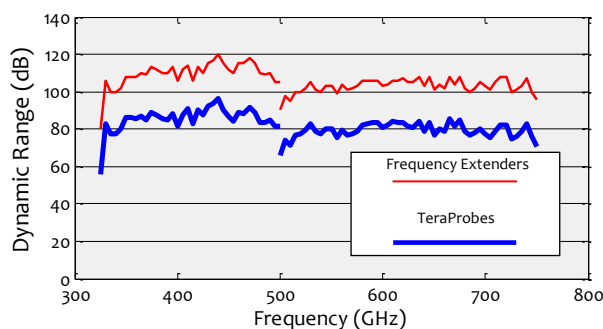
Specifications >

Frequency of operation:	50 GHz – 1.2 THz (limited only by VNAX)
Measurement Repeatability [†]	
Phase Deviation (degrees)	0.6053 (@ 625 GHz)
Magnitude Deviation	0.74 % (@ 625 GHz)
Dynamic Range [‡] (using WR2.2 and WR1.5 VDI Frequency Extenders)	
Typical	>80 dB

[†] Typical repeatability test (S_{11}) on a 25-measurement dataset using five offset short standards



[‡]Dynamic range using VDI frequency extenders (VNAX)



ⁱ A vector network analyzer and frequency extenders are required to conduct measurements.